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Correction: Growth of p/n-type BiFeO₃ thin films for construction of a bilayer p–n junction for photodegradation of organic pollutants

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Correction for 'Growth of p/n-type BiFeO₃ thin films for construction of a bilayer p–n junction for photodegradation of organic pollutants' by Hao-Yun Tu *et al.*, *J. Mater. Chem. A*, 2024, 12, 12752–12761, <https://doi.org/10.1039/D4TA01615G>.

The authors regret that an incorrect version of Fig. 1 was included in the originally published article. The correct version of Fig. 1 is shown below.

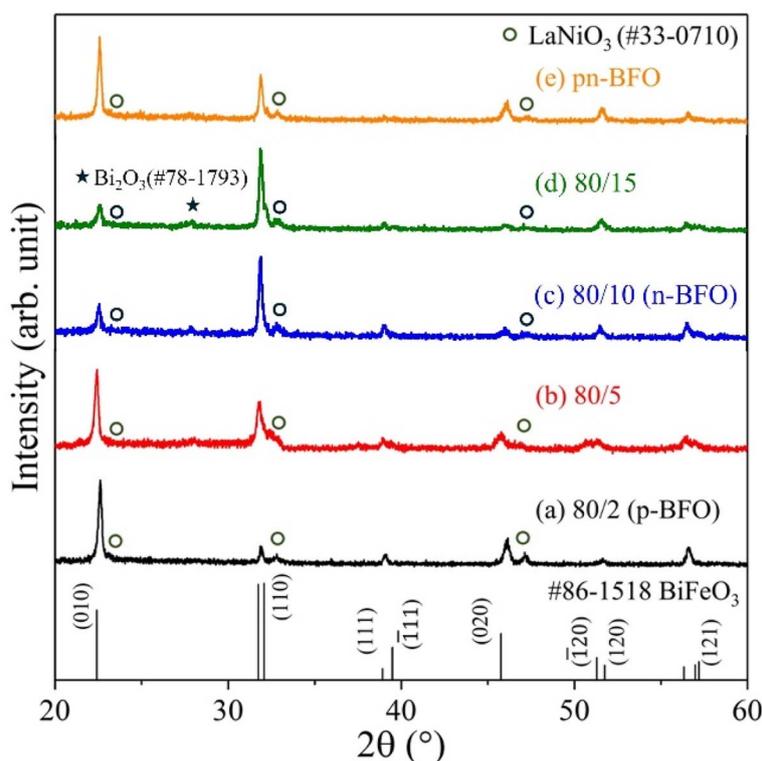


Fig. 1 XRD θ – 2θ scans. Single layer of BFO deposited with the Ar/O₂ ratios of (a) 80/2 (p-type), (b) 80/5, (c) 80/10 (n-type), and (d) 80/15, respectively. (e) pn bilayer.

The Royal Society of Chemistry apologises for these errors and any consequent inconvenience to authors and readers.

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